

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

6050/54207 (LBE-B-1506)

Application Number

09/608,311

Applicant(s)

XIAO-DONG XIANG et al.


Filing Date

JUNE 30, 2000

Group Art Unit

2829

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PL		5,559,328	09/1996	Weiss et al.	250	306	
		5,619,035	04/1997	Weiss et al.	250	306	
		5,821,410	10/1998	Xiang et al.	73	105	
		5,900,618	05/1999	Anlage et al.	250	201.3	
		6,173,604	01/2001	Xiang et al.	73	105	
							
						TC 2000 10/1/2001	

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
PL		WO 99/16102	04/1999	PCT/US98/19764				
PL		117,656	11/2000	Taiwan (R.O.C.)				✓

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

A1	Synge, E.H., "A SUGGESTED METHOD FOR EXTENDING MICROSCOPIC RESOLUTION INTO THE ULTRA-MICROSCOPIC REGION," Philos Magazine, Vol. 6, 1928, pp. 356-362.
A2	Sooahoo, R.F., "A MICROWAVE MAGNETIC MICROSCOPE," Journal of Applied Physics, Vol. 33, No. 3, March, 1962, pp. 1276-1277.

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A15 Gao, Chen, Xiang, X.-D., "QUANTITATIVE MICROWAVE NEAR-FIELD MICROSCOPY OF DIELECTRIC PROPERTIES," Review of Scientific Instruments, vol. 69, No. 11, November, 1998, pp. 3846-3851.

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A17 Gao, Chen, et al., "QUANTITATIVE MICROWAVE EVANESCENT MICROSCOPY," Applied Physics Letters, Vol. 75, No. 19, 8 November, 1999, pp. 3005-3007, with ERRATA published in Applied Physics Letters, Vol. 76, No. 5, 31 January 2000, pp. 656.



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